5126 5126 	Subclass	SSUE CLASSIFICATION
09/9551 09/9551	Class	SSUE CLA

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PATENT NUMBER

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O.I.P.E. PATENT DATE SCANNED

APPLICATION NO. CONT/PRIOR SUBCLASS CLASS ART UNIT **EXAMINER** 09/955126 000 1746 Keum Lee Yong Ko In Hwang

Method for cleaning damaged layers and polymer residue from semiconductor device

## PREPARED AND APPROVED FOR ISSUE

ISSUING CLASSIFICATION								
ORIG	SINAL	CROSS REFERENCE(S)				مرجع		
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
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TERMINAL		DRAWINGS	·	CLAIMS ALLOWED		
└─ DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.	
a) The term of this patent			· <del>-</del> ·	NOTICE OF ALL	OWANCE MAILED	
subsequent to (date) has been disclaimed.	(Assistant Examiner)		(Date)			
b) The term of this patent shall not extend beyond the expiration date					_	
of U.S Patent. No				ISSUE FEE		
<u> </u>				Amount Due	Date Paid	
	(Primary Examiner) (Date)					
c) The terminalmonths of				ISSUE BATCH NUMBER		
this patent have been disclaimed.	(Legal Instruments Examiner) (Date)					
WARNING:						
The information disclosed herein may be res Possession outside the U.S. Patent & Trader					i, Sections 122, 181 and 368.	

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(LABEL AREA)